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### **Understanding Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### **Details**

Product Status	Active
Number of LABs/CLBs	21000
Number of Logic Elements/Cells	84000
Total RAM Bits	3833856
Number of I/O	118
Number of Gates	-
Voltage - Supply	1.045V ~ 1.155V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	285-LFBGA, CSPBGA
Supplier Device Package	285-CSFBGA (10x10)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/lattice-semiconductor/lfe5um-85f-6mg285i">https://www.e-xfl.com/product-detail/lattice-semiconductor/lfe5um-85f-6mg285i</a>

## 2. Architecture

### 2.1. Overview

Each ECP5/ECP5-5G device contains an array of logic blocks surrounded by Programmable I/O Cells (PIC). Interspersed between the rows of logic blocks are rows of sysMEM™ Embedded Block RAM (EBR) and rows of sysDSP™ Digital Signal Processing slices, as shown in [Figure 2.1](#) on page 13. The LFE5-85 devices have three rows of DSP slices, the LFE5-45 devices have two rows, and both LFE5-25 and LFE5-12 devices have one. In addition, the LFE5UM/LFE5UM5G devices contain SERDES Duals on the bottom of the device.

The Programmable Functional Unit (PFU) contains the building blocks for logic, arithmetic, RAM and ROM functions. The PFU block is optimized for flexibility, allowing complex designs to be implemented quickly and efficiently. Logic Blocks are arranged in a two-dimensional array.

The ECP5/ECP5-5G devices contain one or more rows of sysMEM EBR blocks. sysMEM EBRs are large, dedicated 18 Kb fast memory blocks. Each sysMEM block can be configured in a variety of depths and widths as RAM or ROM. In addition, ECP5/ECP5-5G devices contain up to three rows of DSP slices. Each DSP slice has multipliers and adder/accumulators, which are the building blocks for complex signal processing capabilities.

The ECP5 devices feature up to four embedded 3.2 Gb/s SERDES channels, and the ECP5-5G devices feature up to four embedded 5 Gb/s SERDES channels. Each SERDES channel contains independent 8b/10b encoding / decoding, polarity adjust and elastic buffer logic. Each group of two SERDES channels, along with its Physical Coding Sublayer (PCS) block, creates a dual DCU (Dual Channel Unit). The functionality of the SERDES/PCS duals can be controlled by SRAM cell settings during device configuration or by registers that are addressable during device operation. The registers in every dual can be programmed via the SERDES Client Interface (SCI). These DCUs (up to two) are located at the bottom of the devices.

Each PIC block encompasses two PIOs (PIO pairs) with their respective sysI/O buffers. The sysI/O buffers of the ECP5/ECP5-5G devices are arranged in seven banks (eight banks for LFE5-85 devices in caBGA756 and caBGA554 packages), allowing the implementation of a wide variety of I/O standards. One of these banks (Bank 8) is shared with the programming interfaces. Half of the PIO pairs on the left and right edges of the device can be configured as LVDS transmit pairs, and all pairs on left and right can be configured as LVDS receive pairs. The PIC logic in the left and right banks also includes pre-engineered support to aid in the implementation of high speed source synchronous standards such as XGMII, 7:1 LVDS, along with memory interfaces including DDR3 and LPDDR3.

The ECP5/ECP5-5G registers in PFU and sysI/O can be configured to be SET or RESET. After power up and the device is configured, it enters into user mode with these registers SET/RESET according to the configuration setting, allowing the device entering to a known state for predictable system function.

Other blocks provided include PLLs, DLLs and configuration functions. The ECP5/ECP5-5G architecture provides up to four Delay-Locked Loops (DLLs) and up to four Phase-Locked Loops (PLLs). The PLL and DLL blocks are located at the corners of each device.

The configuration block that supports features such as configuration bit-stream decryption, transparent updates and dual-boot support is located at the bottom of each device, to the left of the SERDES blocks. Every device in the ECP5/ECP5-5G family supports a sysCONFIG™ ports located in that same corner, powered by Vccio8, allowing for serial or parallel device configuration.

In addition, every device in the family has a JTAG port. This family also provides an on-chip oscillator and soft error detect capability. The ECP5 devices use 1.1 V and ECP5UM5G devices use 1.2 V as their core voltage.

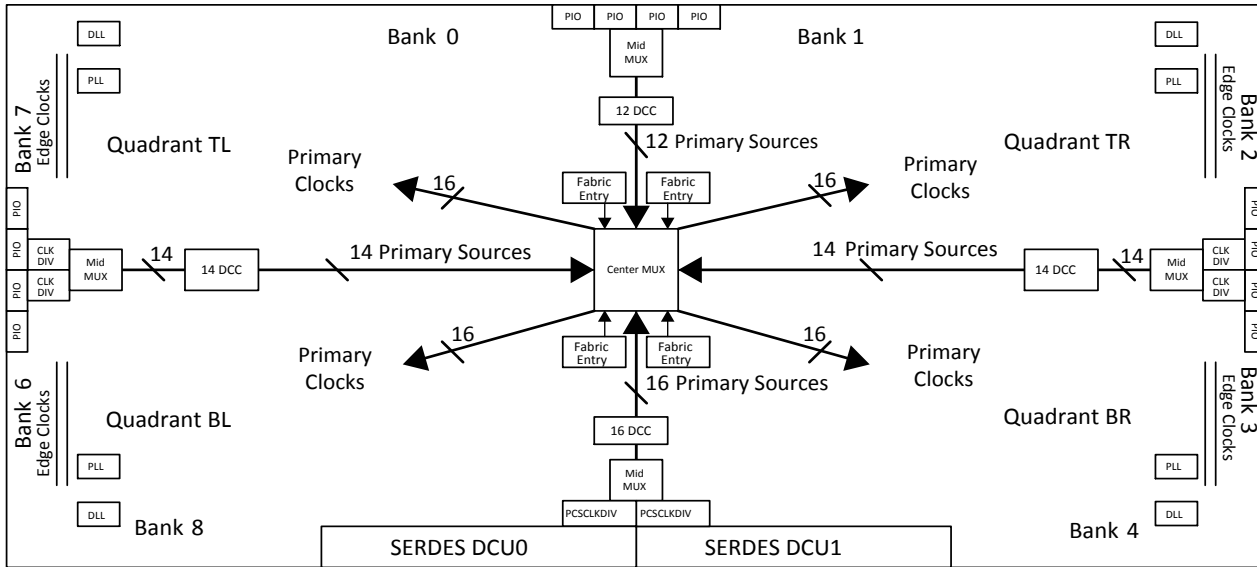


Figure 2.6. LFE5UM/LFE5UM5G-85 Clocking

### 2.5.1. Primary Clocks

The ECP5/ECP5-5G device family provides low-skew, high fan-out clock distribution to all synchronous elements in the FPGA fabric through the Primary Clock Network.

The primary clock network is divided into four clocking quadrants: Top Left (TL), Bottom Left (BL), Top Right (TR), and Bottom Right (BR). Each of these quadrants has 16 clocks that can be distributed to the fabric in the quadrant.

The Lattice Diamond software can automatically route each clock to one of the four quadrants up to a maximum of 16 clocks per quadrant. The user can change how the clocks are routed by specifying a preference in the Lattice Diamond software to locate the clock to specific. The ECP5/ECP5-5G device provides the user with a maximum of 64 unique clock input sources that can be routed to the primary Clock network.

Primary clock sources are:

- Dedicated clock input pins
- PLL outputs
- CLKDIV outputs
- Internal FPGA fabric entries (with minimum general routing)
- SERDES/PCS/PCSDIV clocks
- OSC clock

These sources are routed to one of four clock switches called a Mid Mux. The outputs of the Mid MUX are routed to the center of the FPGA where another clock switch, called the Center MUX, is used to route the primary clock sources to primary clock distribution to the ECP5/ECP5-5G fabric. These routing muxes are shown in Figure 2.6. Since there is a maximum of 60 unique clock input sources to the clocking quadrants, there are potentially 64 unique clock domains that can be used in the ECP5/ECP5-5G Device. For more information about the primary clock tree and connections, refer to [ECP5 and ECP5-5G sysClock PLL/DLL Design and Usage Guide \(TN1263\)](#).

#### 2.5.1.1. Dynamic Clock Control

The Dynamic Clock Control (DCC), Quadrant Clock enable/disable feature allows internal logic control of the quadrant primary clock network. When a clock network is disabled, the clock signal is static and not toggle. All the logic fed by that clock will not toggle, reducing the overall power consumption of the device. The disable function will not create glitch and increase the clock latency to the primary clock network.

This DCC controls the clock sources from the Primary CLOCK MIDMUX before they are fed to the Primary Center MUXes that drive the quadrant clock network. For more information about the DCC, refer to [ECP5 and ECP5-5G sysClock PLL/DLL Design and Usage Guide \(TN1263\)](#).

### 2.8.6. Memory Core Reset

The memory array in the EBR utilizes latches at the A and B output ports. These latches can be reset asynchronously or synchronously. RSTA and RSTB are local signals, which reset the output latches associated with Port A and Port B, respectively. The Global Reset (GSRN) signal can reset both ports. The output data latches and associated resets for both ports are as shown in Figure 2.12.

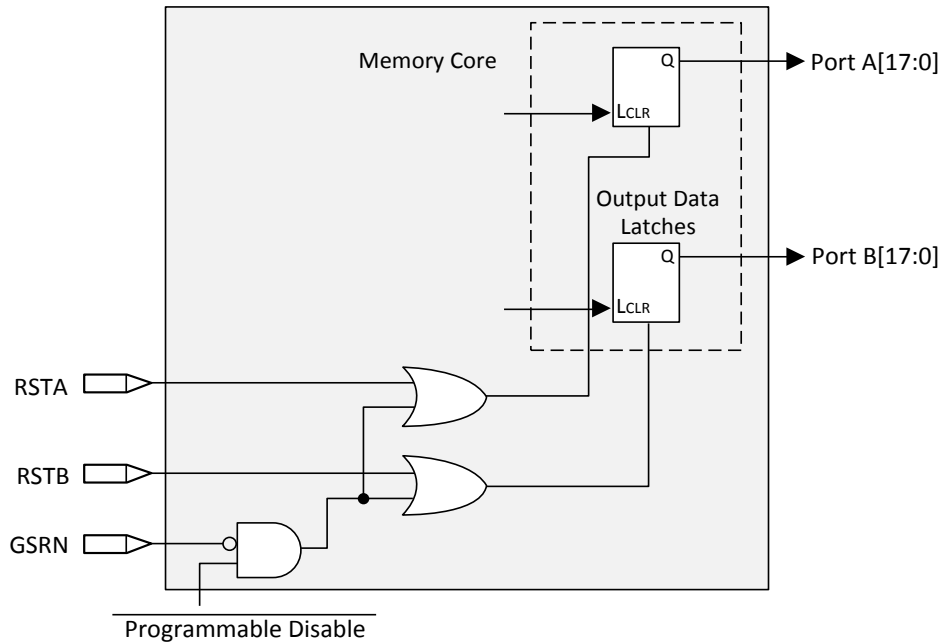


Figure 2.12. Memory Core Reset

For further information on the sysMEM EBR block, see the list of technical documentation in [Supplemental Information](#) section on page 102.

## 2.9. sysDSP™ Slice

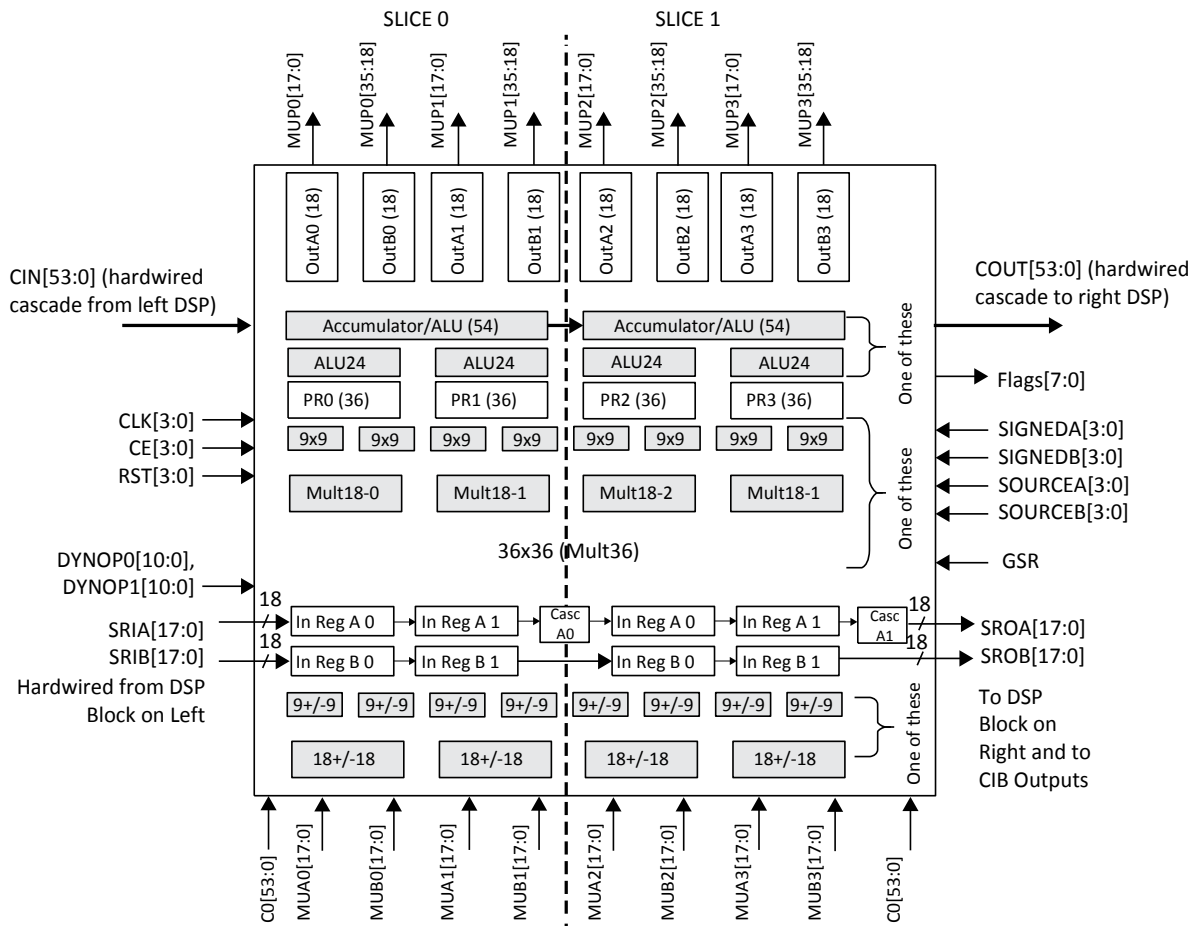
The ECP5/ECP5-5G family provides an enhanced sysDSP architecture, making it ideally suited for low-cost, high-performance Digital Signal Processing (DSP) applications. Typical functions used in these applications are Finite Impulse Response (FIR) filters, Fast Fourier Transforms (FFT) functions, Correlators, Reed-Solomon/Turbo/Convolution encoders and decoders. These complex signal processing functions use similar building blocks such as multiply-adders and multiply-accumulators.

### 2.9.1. sysDSP Slice Approach Compared to General DSP

Conventional general-purpose DSP chips typically contain one to four (Multiply and Accumulate) MAC units with fixed data-width multipliers; this leads to limited parallelism and limited throughput. Their throughput is increased by higher clock speeds. In the ECP5/ECP5-5G device family, there are many DSP slices that can be used to support different data widths. This allows designers to use highly parallel implementations of DSP functions. Designers can optimize DSP performance vs. area by choosing appropriate levels of parallelism. Figure 2.13 compares the fully serial implementation to the mixed parallel and serial implementation.

- 5\*5 and larger size 2D blocks – Semi internal DSP Slice support
- Flexible saturation and rounding options to satisfy a diverse set of applications situations
- Flexible cascading across DSP slices
  - Minimizes fabric use for common DSP and ALU functions
  - Enables implementation of FIR Filter or similar structures using dedicated sysDSP slice resources only
  - Provides matching pipeline registers
  - Can be configured to continue cascading from one row of sysDSP slices to another for longer cascade chains
- Flexible and Powerful Arithmetic Logic Unit (ALU) Supports:
  - Dynamically selectable ALU OPCODE
  - Ternary arithmetic (addition/subtraction of three inputs)
  - Bit-wise two-input logic operations (AND, OR, NAND, NOR, XOR and XNOR)
  - Eight flexible and programmable ALU flags that can be used for multiple pattern detection scenarios, such as, overflow, underflow and convergent rounding.
  - Flexible cascading across slices to get larger functions
- RTL Synthesis friendly synchronous reset on all registers, while still supporting asynchronous reset for legacy users
- Dynamic MUX selection to allow Time Division Multiplexing (TDM) of resources for applications that require processor-like flexibility that enables different functions for each clock cycle

For most cases, as shown in [Figure 2.14](#), the ECP5/ECP5-5G sysDSP slice is backwards-compatible with the LatticeECP2™ and LatticeECP3™ sysDSP block, such that, legacy applications can be targeted to the ECP5/ ECP5-5G sysDSP slice. [Figure 2.14](#) shows the diagram of sysDSP, and [Figure 2.15](#) shows the detailed diagram.



**Figure 2.14. Simplified sysDSP Slice Block Diagram**

### 2.11.1.1. Input FIFO

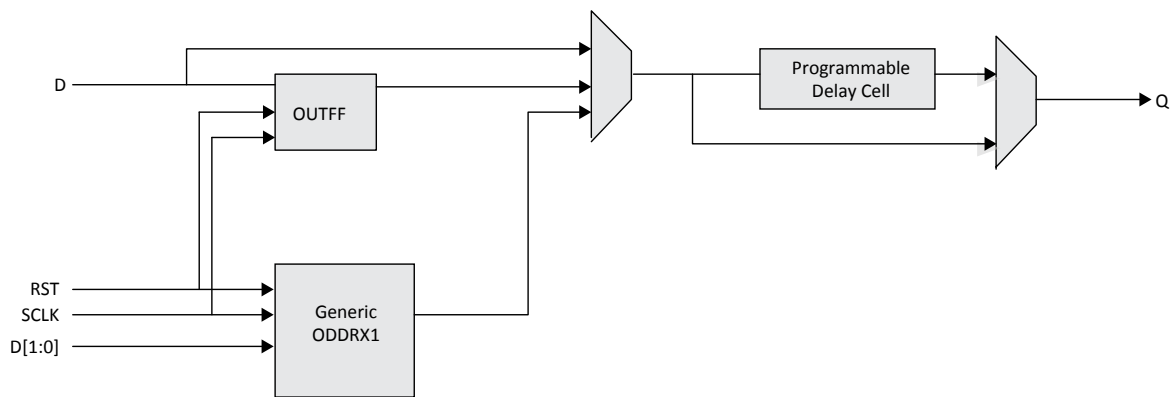
The ECP5/ECP5-5G PIO has dedicated input FIFO per single-ended pin for input data register for DDR Memory interfaces. The FIFO resides before the gearing logic. It transfers data from DQS domain to continuous ECLK domain. On the Write side of the FIFO, it is clocked by DQS clock which is the delayed version of the DQS Strobe signal from DDR memory. On the Read side of FIFO, it is clocked by ECLK. ECLK may be any high speed clock with identical frequency as DQS (the frequency of the memory chip). Each DQS group has one FIFO control block. It distributes FIFO read/write pointer to every PIC in same DQS group. DQS Grouping and DQS Control Block is described in [DDR Memory Support](#) section on page 35.

**Table 2.8. Input Block Port Description**

Name	Type	Description
D	Input	High Speed Data Input
Q[1:0]/Q[3:0]/Q[6:0]	Output	Low Speed Data to the device core
RST	Input	Reset to the Output Block
SCLK	Input	Slow Speed System Clock
ECLK	Input	High Speed Edge Clock
DQS	Input	Clock from DQS control Block used to clock DDR memory data
ALIGNWD	Input	Data Alignment signal from device core.

### 2.11.2. Output Register Block

The output register block registers signal from the core of the device before they are passed to the sysIO buffers. ECP5/ECP5-5G output data path has output programmable flip flops and output gearing logic. On the left and right sides, the output register block can support 1x, 2x and 7:1 gearing enabling high speed DDR interfaces and DDR memory interfaces. On the top side, the banks support 1x gearing. ECP5/ECP5-5G output data path diagram is shown in [Figure 2.19](#). The programmable delay cells are also available in the output data path. For detailed description of the output register block modes and usage, refer to [ECP5 and ECP5-5G High-Speed I/O Interface \(TN1265\)](#).



**Figure 2.19. Output Register Block on Top Side**

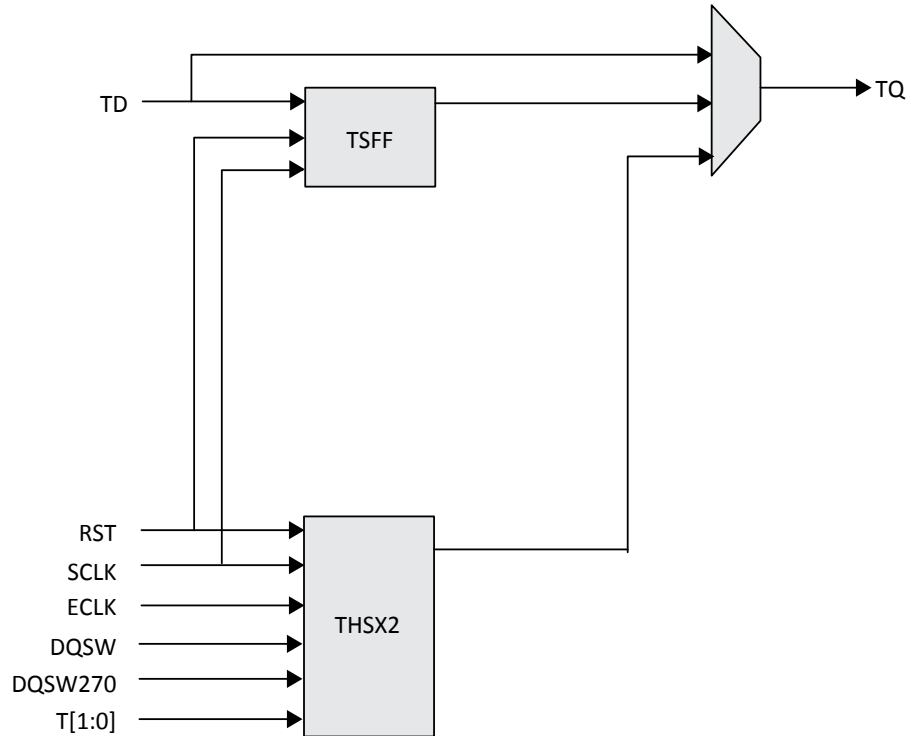


Figure 2.22. Tristate Register Block on Left and Right Sides

Table 2.10. Tristate Block Port Description

Name	Type	Description
TD	Input	Tristate Input to Tristate SDR Register
RST	Input	Reset to the Tristate Block
TD[1:0]	Input	Tristate input to TSHX2 function
SCLK	Input	Slow Speed System Clock
ECLK	Input	High Speed Edge Clock
DQSW	Input	Clock from DQS control Block used to generate DDR memory DQS output
DQSW270	Input	Clock from DQS control Block used to generate DDR memory DQ output
TQ	Output	Output of the Tristate block

## 2.13. DDR Memory Support

### 2.13.1. DQS Grouping for DDR Memory

Certain PICs have additional circuitry to allow the implementation of high-speed source synchronous and DDR2, DDR3, LPDDR2 or LPDDR3 memory interfaces. The support varies by the edge of the device as detailed below.

The left and right sides of the PIC have fully functional elements supporting DDR2, DDR3, LPDDR2 or LPDDR3 memory interfaces. Every 16 PIOs on the left and right sides are grouped into one DQS group, as shown in Figure 2.23 on page 36. Within each DQS group, there are two pre-placed pins for DQS and DQS# signals. The rest of the pins in the DQS group can be used as DQ signals and DM signal. The number of pins in each DQS group bonded out is package dependent. DQS groups with less than 11 pins bonded out can only be used for LPDDR2/3 Command/ Address busses. In DQS groups with more than 11 pins bonded out, up to two pre-defined pins are assigned to be used as "virtual" VCCIO, by driving these pins to HIGH, with the user connecting these pins to VCCIO power supply. These connections create "soft" connections to VCCIO thru these output pins, and make better connections on VCCIO to help to reduce SSO noise. For details, refer to [ECP5 and ECP5-5G High-Speed I/O Interface \(TN1265\)](#).

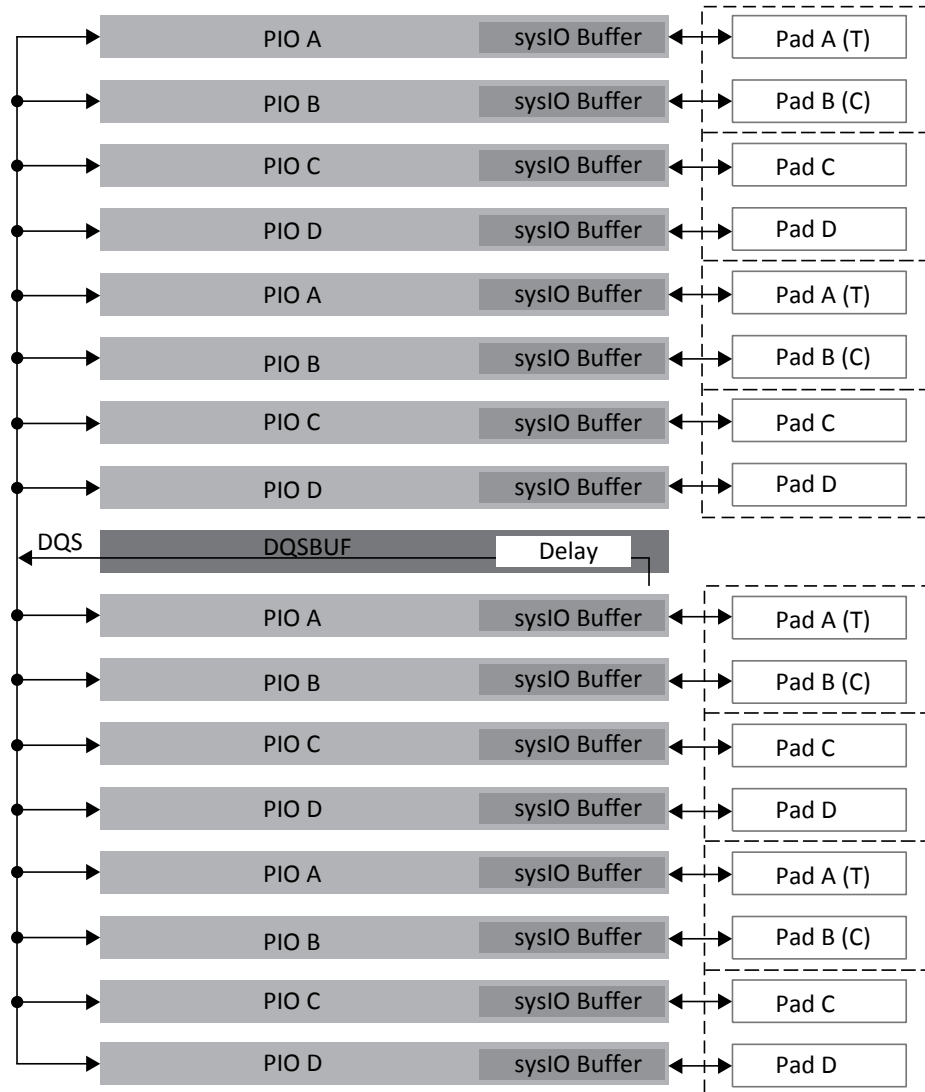


Figure 2.23. DQS Grouping on the Left and Right Edges

### 2.13.2. DLL Calibrated DQS Delay and Control Block (DQSBUF)

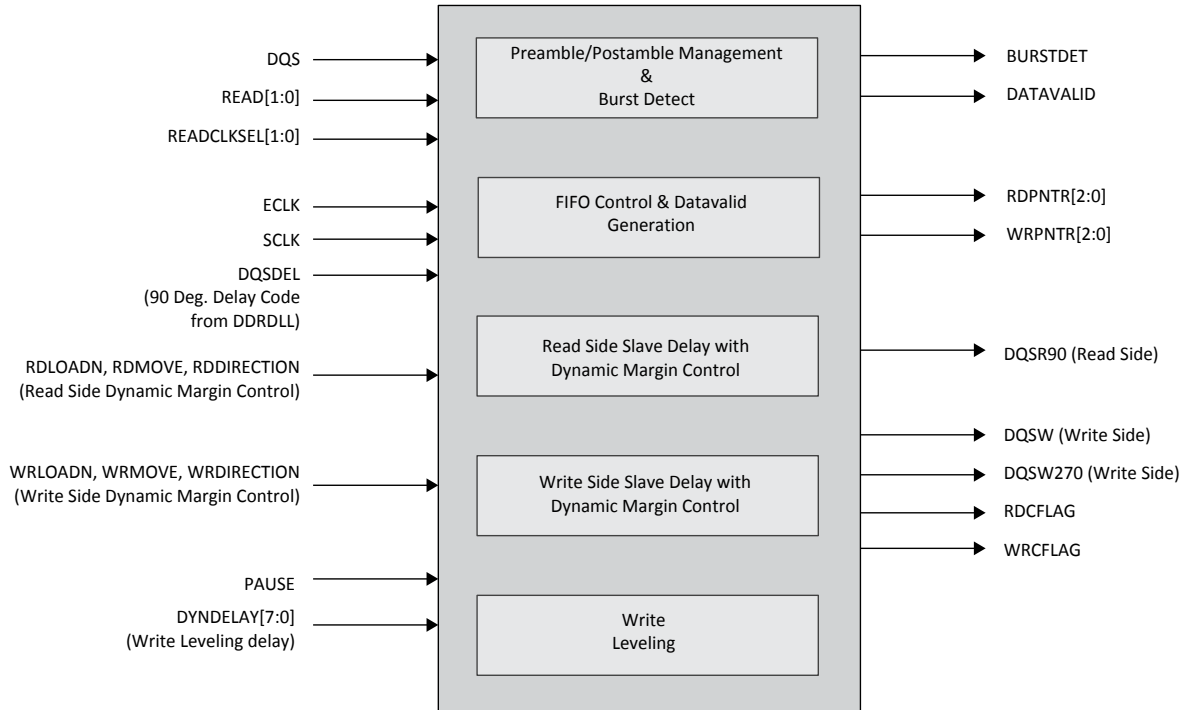
To support DDR memory interfaces (DDR2/3, LPDDR2/3), the DQS strobe signal from the memory must be used to capture the data (DQ) in the PIC registers during memory reads. This signal is output from the DDR memory device aligned to data transitions and must be time shifted before it can be used to capture data in the PIC. This time shifted is achieved by using DQSDEL programmable delay line in the DQS Delay Block (DQS Delay circuit). The DQSDEL is implemented as a slave delay line and works in conjunction with a master DDRDLL.

This block also includes slave delay line to generate delayed clocks used in the write side to generate DQ and DQS with correct phases within one DQS group. There is a third delay line inside this block used to provide write leveling feature for DDR write if needed.

Each of the read and write side delays can be dynamically shifted using margin control signals that can be controlled by the core logic.

FIFO Control Block shown in [Figure 2.24](#) generates the Read and Write Pointers for the FIFO block inside the Input Register Block. These pointers are generated to control the DQS to ECLK domain crossing using the FIFO module.





**Figure 2.24. DQS Control and Delay Block (DQSBUF)**

**Table 2.11. DQSBUF Port List Description**

Name	Type	Description
DQS	Input	DDR memory DQS strobe
READ[1:0]	Input	Read Input from DDR Controller
READCLKSEL[1:0]	Input	Read pulse selection
SCLK	Input	Slow System Clock
ECLK	Input	High Speed Edge Clock (same frequency as DDR memory)
DQSDEL	Input	90° Delay Code from DDRDLL
RDLOADN, RDMOVE, RDDIRECTION	Input	Dynamic Margin Control ports for Read delay
WRLOADN, WRMOVE, WRDIRECTION	Input	Dynamic Margin Control ports for Write delay
PAUSE	Input	Used by DDR Controller to Pause write side signals during DDRDLL Code update or Write Leveling
DYNDELAY[7:0]	Input	Dynamic Write Leveling Delay Control
DQSR90	Output	90° delay DQS used for Read
DQSW270	Output	90° delay clock used for DQ Write
DQSW	Output	Clock used for DQS Write
RDPNTR[2:0]	Output	Read Pointer for IFIFO module
WRPNTR[2:0]	Output	Write Pointer for IFIFO module
DATAVALID	Output	Signal indicating start of valid data
BURSTDET	Output	Burst Detect indicator
RDFLAG	Output	Read Dynamic Margin Control output to indicate max value
WRFLAG	Output	Write Dynamic Margin Control output to indicate max value

## 2.14. sysI/O Buffer

Each I/O is associated with a flexible buffer referred to as a sysI/O buffer. These buffers are arranged around the periphery of the device in groups referred to as banks. The sysI/O buffers allow users to implement the wide variety of standards that are found in today’s systems including LVDS, HSUL, BLVDS, SSTL Class I and II, LVCMOS, LVTTTL, LVPECL, and MIPI.

### 2.14.1. sysI/O Buffer Banks

ECP5/ECP5-5G devices have seven sysI/O buffer banks, two banks per side at Top, Left and Right, plus one at the bottom left side. The bottom left side bank (Bank 8) is a shared I/O bank. The I/Os in that bank contains both dedicated and shared I/O for sysConfig function. When a shared pin is not used for configuration, it is available as a user I/O. For LFE5-85 devices, there is an additional I/O bank (Bank 4) that is not available in other device in the family.

In ECP5/ECP5-5G devices, the Left and Right sides are tailored to support high performance interfaces, such as DDR2, DDR3, LPDDR2, LPDDR3 and other high speed source synchronous standards. The banks on the Left and Right sides of the devices feature LVDS input and output buffers, data-width gearing, and DQSBUF block to support DDR2/3 and LPDDR2/3 interfaces. The I/Os on the top and bottom banks do not have LVDS input and output buffer, and gearing logic, but can use LVCMOS to emulate most of differential output signaling.

Each sysI/O bank has its own I/O supply voltage ( $V_{CCIO}$ ). In addition, the banks on the Left and Right sides of the device, have voltage reference input (shared I/O pin),  $V_{REF1}$  per bank, which allow it to be completely independent of each other. The  $V_{REF}$  voltage is used to set the threshold for the referenced input buffers, such as SSTL. Figure 2.25 shows the seven banks and their associated supplies.

In ECP5/ECP5-5G devices, single-ended output buffers and ratioed input buffers (LVTTTL, and LVCMOS) are powered using  $V_{CCIO}$ . LVTTTL, LVCMOS33, LVCMOS25 and LVCMOS12 can also be set as fixed threshold inputs independent of  $V_{CCIO}$ .

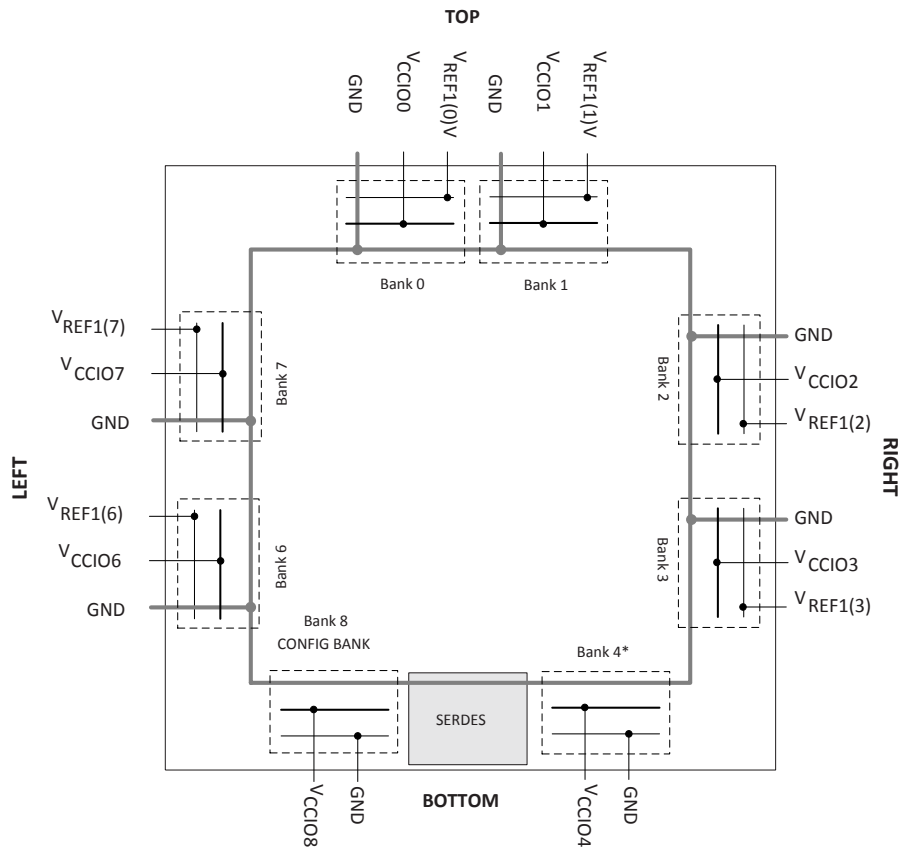


Figure 2.25. ECP5/ECP5-5G Device Family Banks

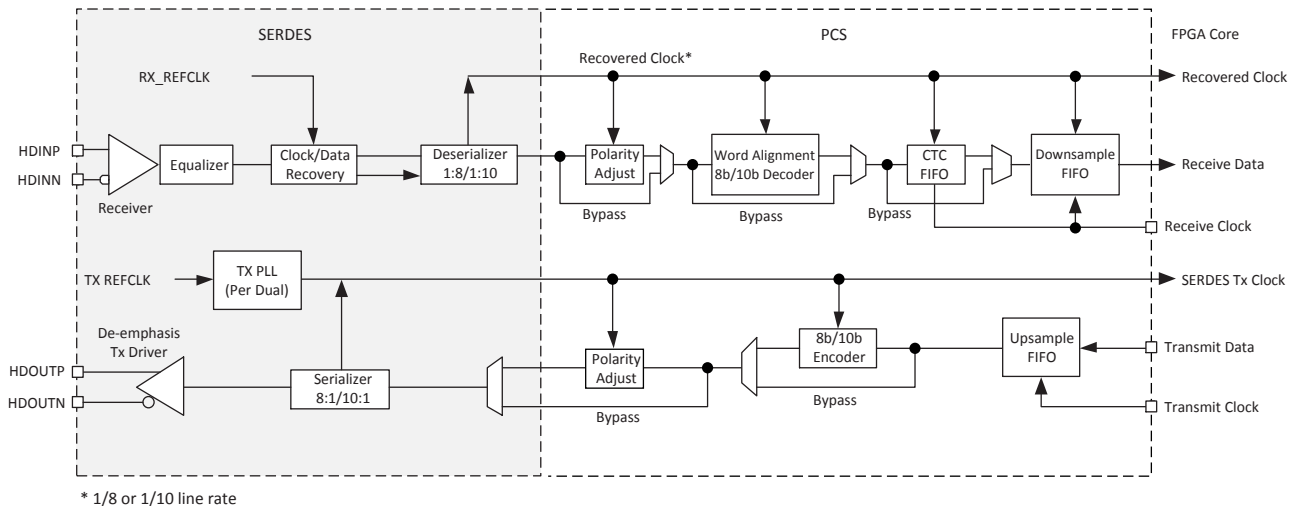
**Table 2.14. Available SERDES Duals per LFE5UM/LFE5UM5G Devices**

Package	LFE5UM/LFE5UM5G-25	LFE5UM/LFE5UM5G-45	LFE5UM/LFE5UM5G-85
285 csFBGA	1	1	1
381 caBGA	1	2	2
554 caBGA	—	2	2
756 caBGA	—	—	2

### 2.15.1. SERDES Block

A SERDES receiver channel may receive the serial differential data stream, equalize the signal, perform Clock and Data Recovery (CDR) and de-serialize the data stream before passing the 8- or 10-bit data to the PCS logic. The SERDES transmitter channel may receive the parallel 8- or 10-bit data, serialize the data and transmit the serial bit stream through the differential drivers. [Figure 2.28](#) shows a single-channel SERDES/PCS block. Each SERDES channel provides a recovered clock and a SERDES transmit clock to the PCS block and to the FPGA core logic.

Each transmit channel, receiver channel, and SERDES PLL shares the same power supply (VCCA). The output and input buffers of each channel have their own independent power supplies (VCCHTX and VCCHRX).



**Figure 2.28. Simplified Channel Block Diagram for SERDES/PCS Block**

### 2.15.2. PCS

As shown in [Figure 2.28](#), the PCS receives the parallel digital data from the deserializer and selects the polarity, performs word alignment, decodes (8b/10b), provides Clock Tolerance Compensation and transfers the clock domain from the recovered clock to the FPGA clock via the Down Sample FIFO.

For the transmit channel, the PCS block receives the parallel data from the FPGA core, encodes it with 8b/10b, selects the polarity and passes the 8/10 bit data to the transmit SERDES channel.

The PCS also provides bypass modes that allow a direct 8-bit or 10-bit interface from the SERDES to the FPGA logic. The PCS interface to the FPGA can also be programmed to run at 1/2 speed for a 16-bit or 20-bit interface to the FPGA logic.

Some of the enhancements in LFE5UM/LFE5UM5G SERDES/PCS include:

- Higher clock/channel granularity: Dual channel architecture provides more clock resource per channel.
- Enhanced Tx de-emphasis: Programmable pre- and post-cursors improves Tx output signaling
- Bit-slip function in PCS: Improves logic needed to perform Word Alignment function

Refer to [ECP5 and ECP5-5G SERDES/PCS Usage Guide \(TN1261\)](#) for more information.

### 3.13. sysIO Single-Ended DC Electrical Characteristics

Table 3.12. Single-Ended DC Characteristics

Input/Output Standard	V <sub>IL</sub>		V <sub>IH</sub>		V <sub>OL</sub> Max (V)	V <sub>OH</sub> Min (V)	I <sub>OL</sub> <sup>1</sup> (mA)	I <sub>OH</sub> <sup>1</sup> (mA)
	Min (V)	Max (V)	Min (V)	Max (V)				
LVC MOS33	-0.3	0.8	2.0	3.465	0.4	V <sub>CCIO</sub> - 0.4	16, 12, 8, 4	-16, -12, -8, -4
LVC MOS25	-0.3	0.7	1.7	3.465	0.4	V <sub>CCIO</sub> - 0.4	12, 8, 4	-12, -8, -4
LVC MOS18	-0.3	0.35 V <sub>CCIO</sub>	0.65 V <sub>CCIO</sub>	3.465	0.4	V <sub>CCIO</sub> - 0.4	12, 8, 4	-12, -8, -4
LVC MOS15	-0.3	0.35 V <sub>CCIO</sub>	0.65 V <sub>CCIO</sub>	3.465	0.4	V <sub>CCIO</sub> - 0.4	8, 4	-8, -4
LVC MOS12	-0.3	0.35 V <sub>CCIO</sub>	0.65 V <sub>CCIO</sub>	3.465	0.4	V <sub>CCIO</sub> - 0.4	8, 4	-8, -4
LVTTL33	-0.3	0.8	2.0	3.465	0.4	V <sub>CCIO</sub> - 0.4	16, 12, 8, 4	-16, -12, -8, -4
SSTL18_I (DDR2 Memory)	-0.3	V <sub>REF</sub> - 0.125	V <sub>REF</sub> + 0.125	3.465	0.4	V <sub>CCIO</sub> - 0.4	6.7	-6.7
SSTL18_II	-0.3	V <sub>REF</sub> -	V <sub>REF</sub> + 0.125	3.465	0.28	V <sub>CCIO</sub> - 0.28	13.4	-13.4
SSTL15_I (DDR3 Memory)	-0.3	V <sub>REF</sub> - 0.1	V <sub>REF</sub> + 0.1	3.465	0.31	V <sub>CCIO</sub> - 0.31	7.5	-7.5
SSTL15_II (DDR3 Memory)	-0.3	V <sub>REF</sub> - 0.1	V <sub>REF</sub> + 0.1	3.465	0.31	V <sub>CCIO</sub> - 0.31	8.8	-8.8
SSTL135_I (DDR3L Memory)	-0.3	V <sub>REF</sub> - 0.09	V <sub>REF</sub> + 0.09	3.465	0.27	V <sub>CCIO</sub> - 0.27	7	-7
SSTL135_II (DDR3L Memory)	-0.3	V <sub>REF</sub> - 0.09	V <sub>REF</sub> + 0.09	3.465	0.27	V <sub>CCIO</sub> - 0.27	8	-8
MIPI D-PHY (LP) <sup>3</sup>	-0.3	0.55	0.88	3.465	—	—	—	—
HSUL12 (LPDDR2/3 Memory)	-0.3	V <sub>REF</sub> - 0.1	V <sub>REF</sub> + 0.1	3.465	0.3	V <sub>CCIO</sub> - 0.3	4	-4

**Notes:**

1. For electromigration, the average DC current drawn by the I/O pads within a bank of I/Os shall not exceed 10 mA per I/O (All I/Os used in the same V<sub>CCIO</sub>).
2. Not all IO types are supported in all banks. Refer to [ECP5 and ECP5-5G sysIO Usage Guide \(TN1262\)](#) for details.
3. MIPI D-PHY LP input can be implemented by powering V<sub>CCIO</sub> to 1.5V, and select MIPI LP primitive to meet MIPI Alliance spec on V<sub>IH</sub> and V<sub>IL</sub>. It can also be implemented as LVC MOS12 with V<sub>CCIO</sub> at 1.2V, which would meet V<sub>IH</sub>/V<sub>IL</sub> spec on LVC MOS12.

### 3.14.8. SLVS

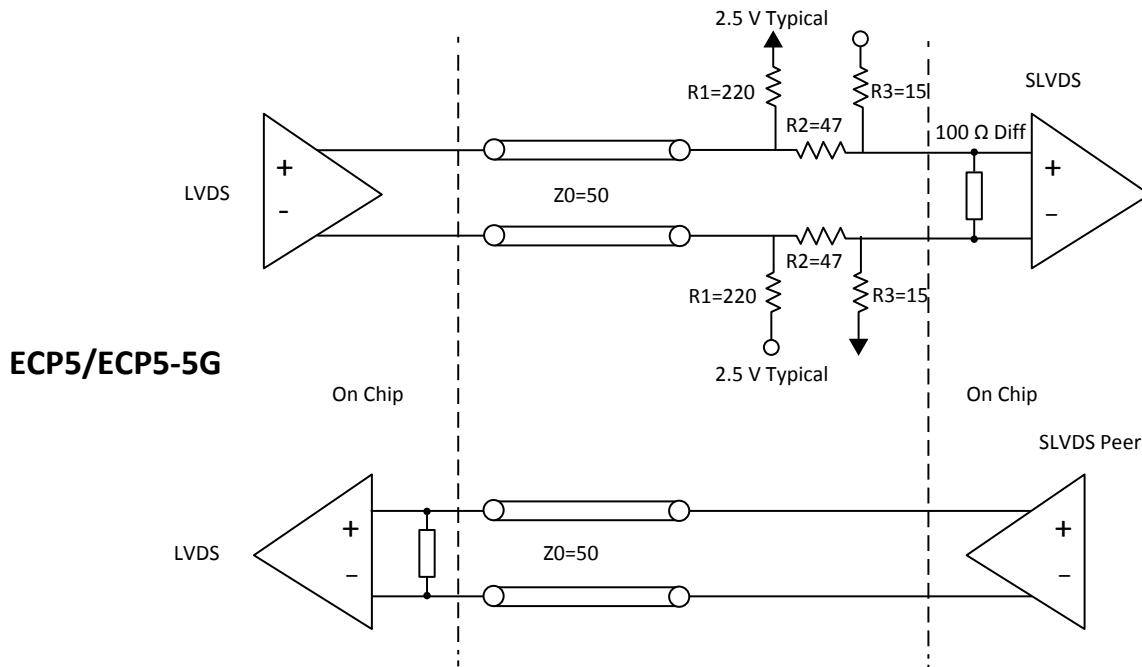
Scalable Low-Voltage Signaling (SLVS) is based on a point-to-point signaling method defined in the JEDEC JESD8-13 (SLVS-400) standard. This standard evolved from the traditional LVDS standard and relies on the advantage of its use of smaller voltage swings and a lower common-mode voltage. The 200 mV (400 mV p-p) SLVS swing contributes to a reduction in power.

The ECP5/ECP5-5G devices can receive differential input up to 800 Mb/s with its LVDS input buffer. This LVDS input buffer is used to meet the SLVS input standard specified by the JEDEC standard. The SLVS output parameters are compared to ECP5/ECP5-5G LVDS input parameters, as listed in Table 3.18.

**Table 3.18. Input to SLVS**

Parameter	ECP5/ECP5-5G LVDS Input	SLVS Output	Unit
Vcm (min)	50	150	mV
Vcm (max)	2350	250	mV
Differential Voltage (min)	100	140	mV
Differential Voltage (max)	—	270	mV

ECP5/ECP5-5G does not support SLVS output. However, SLVS output can be created using ECP5/ECP5-5G LVDS outputs by level shift to meet the low Vcm/Vod levels required by SLVS. Figure 3.5 shows how the LVDS output can be shifted external to meet SLVS levels.



**Figure 3.5. SLVS Interface**

### 3.15. Typical Building Block Function Performance

**Table 3.19. Pin-to-Pin Performance**

Function	-8 Timing	Unit
<b>Basic Functions</b>		
16-Bit Decoder	5.06	ns
32-Bit Decoder	6.08	ns
64-Bit Decoder	5.06	ns
4:1 Mux	4.45	ns
8:1 Mux	4.63	ns
16:1 Mux	4.81	ns
32:1 Mux	4.85	ns

**Notes:**

1. I/Os are configured with LVCMOS25 with  $V_{CCIO}=2.5$ , 12 mA drive.
2. These functions were generated using Lattice Diamond design software tool. Exact performance may vary with the device and the design software tool version. The design software tool uses internal parameters that have been characterized but are not tested on every device.
3. Commercial timing numbers are shown. Industrial numbers are typically slower and can be extracted from Lattice Diamond design software tool.

## 3.25. PCI Express Electrical and Timing Characteristics

### 3.25.1. PCIe (2.5 Gb/s) AC and DC Characteristics

Over recommended operating conditions.

**Table 3.30. PCIe (2.5 Gb/s)**

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
<b>Transmit<sup>1</sup></b>						
UI	Unit interval	—	399.88	400	400.12	ps
V <sub>TX-DIFF_P-P</sub>	Differential peak-to-peak output	—	0.8	1.0	1.2	V
V <sub>TX-DE-RATIO</sub>	De-emphasis differential output voltage ratio	—	-3	-3.5	-4	dB
V <sub>TX-CM-AC_P</sub>	RMS AC peak common-mode output voltage	—	—	—	20	mV
V <sub>TX-RCV-DETECT</sub>	Amount of voltage change allowed during receiver detection	—	—	—	600	mV
V <sub>TX-CM-DC</sub>	Tx DC common mode voltage	—	0	—	V <sub>CCHTX</sub>	V
I <sub>TX-SHORT</sub>	Output short circuit current	V <sub>TX-D+</sub> =0.0 V V <sub>TX-D-</sub> =0.0 V	—	—	90	mA
Z <sub>TX-DIFF-DC</sub>	Differential output impedance	—	80	100	120	Ω
RL <sub>TX-DIFF</sub>	Differential return loss	—	10	—	—	dB
RL <sub>TX-CM</sub>	Common mode return loss	—	6.0	—	—	dB
T <sub>TX-RISE</sub>	Tx output rise time	20% to 80%	0.125	—	—	UI
T <sub>TX-FALL</sub>	Tx output fall time	20% to 80%	0.125	—	—	UI
L <sub>TX-SKEW</sub>	Lane-to-lane static output skew for all lanes in port/link	—	—	—	1.3	ns
T <sub>TX-EYE</sub>	Transmitter eye width	—	0.75	—	—	UI
T <sub>TX-EYE-MEDIAN-TO-MAX-JITTER</sub>	Maximum time between jitter median and maximum deviation from median	—	—	—	0.125	UI
<b>Receive<sup>1,2</sup></b>						
UI	Unit Interval	—	399.88	400	400.12	ps
V <sub>RX-DIFF_P-P</sub>	Differential peak-to-peak input voltage	—	0.34 <sup>3</sup>	—	1.2	V
V <sub>RX-IDLE-DET-DIFF_P-P</sub>	Idle detect threshold voltage	—	65	—	340 <sup>3</sup>	mV
V <sub>RX-CM-AC_P</sub>	RMS AC peak common-mode input voltage	—	—	—	150	mV
Z <sub>RX-DIFF-DC</sub>	DC differential input impedance	—	80	100	120	Ω
Z <sub>RX-DC</sub>	DC input impedance	—	40	50	60	Ω
Z <sub>RX-HIGH-IMP-DC</sub>	Power-down DC input impedance	—	200K	—	—	Ω
RL <sub>RX-DIFF</sub>	Differential return loss	—	10	—	—	dB
RL <sub>RX-CM</sub>	Common mode return loss	—	6.0	—	—	dB

**Notes:**

1. Values are measured at 2.5 Gb/s.
2. Measured with external AC-coupling on the receiver.
3. Not in compliance with PCI Express 1.1 standard.

### 3.25.2. PCIe (5 Gb/s) – Preliminary AC and DC Characteristics

Over recommended operating conditions.

**Table 3.31. PCIe (5 Gb/s)**

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
<b>Transmit<sup>1</sup></b>						
UI	Unit Interval	—	199.94	200	200.06	ps
B <sub>WTX-PKG-PLL2</sub>	Tx PLL bandwidth corresponding to PKGTx-PLL2	—	5	—	16	MHz
P <sub>KGTX-PLL2</sub>	Tx PLL Peaking	—	—	—	1	dB
V <sub>TX-DIFF-PP</sub>	Differential p-p Tx voltage swing	—	0.8	—	1.2	V, p-p
V <sub>TX-DIFF-PP-LOW</sub>	Low power differential p-p Tx voltage swing	—	0.4	—	1.2	V, p-p
V <sub>TX-DE-RATIO-3.5dB</sub>	Tx de-emphasis level ratio at 3.5dB	—	3	—	4	dB
V <sub>TX-DE-RATIO-6dB</sub>	Tx de-emphasis level ratio at 6dB	—	5.5	—	6.5	dB
T <sub>MIN-PULSE</sub>	Instantaneous lone pulse width	—	—	—	—	UI
T <sub>TX-RISE-FALL</sub>	Transmitter rise and fall time	—	—	—	—	UI
T <sub>TX-EYE</sub>	Transmitter Eye, including all jitter sources	—	0.75	—	—	UI
T <sub>TX-DJ</sub>	Tx deterministic jitter > 1.5 MHz	—	—	—	0.15	UI
T <sub>TX-RJ</sub>	Tx RMS jitter < 1.5 MHz	—	—	—	3	ps, RMS
T <sub>RF-MISMATCH</sub>	Tx rise/fall time mismatch	—	—	—	—	UI
R <sub>LTX-DIFF</sub>	Tx Differential Return Loss, including package and silicon	50 MHz < freq < 1.25 GHz	10	—	—	dB
		1.25 GHz < freq < 2.5 GHz	8	—	—	dB
R <sub>LTX-CM</sub>	Tx Common Mode Return Loss, including package and silicon	50 MHz < freq < 2.5 GHz	6	—	—	dB
Z <sub>TX-DIFF-DC</sub>	DC differential Impedance	—	—	—	120	Ω
V <sub>TX-CM-AC-PP</sub>	Tx AC peak common mode voltage, peak-peak	—	—	—	—	mV, p-p
I <sub>TX-SHORT</sub>	Transmitter short-circuit current	—	—	—	90	mA
V <sub>TX-DC-CM</sub>	Transmitter DC common-mode voltage	—	0	—	1.2	V
V <sub>TX-IDLE-DIFF-DC</sub>	Electrical Idle Output DC voltage	—	0	—	5	mV
V <sub>TX-IDLE-DIFF-AC-p</sub>	Electrical Idle Differential Output peak voltage	—	—	—	—	mV
V <sub>TX-RCV-DETECT</sub>	Voltage change allowed during Receiver Detect	—	—	—	600	mV
T <sub>TX-IDLE-MIN</sub>	Min. time in Electrical Idle	—	20	—	—	ns
T <sub>TX-IDLE-SET-TO-IDLE</sub>	Max. time from EI Order Set to valid Electrical Idle	—	—	—	8	ns
T <sub>TX-IDLE-TO-DIFF-DATA</sub>	Max. time from Electrical Idle to valid differential output	—	—	—	8	ns
L <sub>TX-SKEW</sub>	Lane-to-lane output skew	—	—	—	—	ps



## 3.27. XAUI/CPRI LV E.30 Electrical and Timing Characteristics

### 3.27.1. AC and DC Characteristics

Over recommended operating conditions.

**Table 3.33. Transmit**

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
$T_{RF}$	Differential rise/fall time	20% to 80%	—	80	—	ps
$Z_{TX\_DIFF\_DC}$	Differential impedance	—	80	100	120	$\Omega$
$J_{TX\_DDJ}^{2,3}$	Output data deterministic jitter	—	—	—	0.17	UI
$J_{TX\_TJ}^{1,2,3}$	Total output data jitter	—	—	—	0.35	UI

**Notes:**

1. Total jitter includes both deterministic jitter and random jitter.
2. Jitter values are measured with each CML output AC coupled into a 50  $\Omega$  impedance (100  $\Omega$  differential impedance).
3. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.

Over recommended operating conditions.

**Table 3.34. Receive and Jitter Tolerance**

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
$RL_{RX\_DIFF}$	Differential return loss	From 100 MHz to 3.125 GHz	10	—	—	dB
$RL_{RX\_CM}$	Common mode return loss	From 100 MHz to 3.125 GHz	6	—	—	dB
$Z_{RX\_DIFF}$	Differential termination resistance	—	80	100	120	$\Omega$
$J_{RX\_DJ}^{1,2,3}$	Deterministic jitter tolerance (peak-to-peak)	—	—	—	0.37	UI
$J_{RX\_RJ}^{1,2,3}$	Random jitter tolerance (peak-to-peak)	—	—	—	0.18	UI
$J_{RX\_SJ}^{1,2,3}$	Sinusoidal jitter tolerance (peak-to-peak)	—	—	—	0.10	UI
$J_{RX\_TJ}^{1,2,3}$	Total jitter tolerance (peak-to-peak)	—	—	—	0.65	UI
$T_{RX\_EYE}$	Receiver eye opening	—	0.35	—	—	UI

**Notes:**

1. Total jitter includes deterministic jitter, random jitter and sinusoidal jitter.
2. Jitter values are measured with each high-speed input AC coupled into a 50  $\Omega$  impedance.
3. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.

## 3.28. CPRI LV E.24/SGMII(2.5Gbps) Electrical and Timing Characteristics

### 3.28.1. AC and DC Characteristics

**Table 3.35. Transmit**

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
$T_{RF}^1$	Differential rise/fall time	20% to 80%	—	80	—	ps
$Z_{TX\_DIFF\_DC}$	Differential impedance	—	80	100	120	$\Omega$
$J_{TX\_DDJ}^{3,4}$	Output data deterministic jitter	—	—	—	0.17	UI
$J_{TX\_TJ}^{2,3,4}$	Total output data jitter	—	—	—	0.35	UI

**Notes:**

1. Rise and Fall times measured with board trace, connector and approximately 2.5 pf load.
2. Total jitter includes both deterministic jitter and random jitter. The random jitter is the total jitter minus the actual deterministic jitter.
3. Jitter values are measured with each CML output AC coupled into a 50  $\Omega$  impedance (100  $\Omega$  differential impedance).
4. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.

### 3.30. SMPTE SD/HD-SDI/3G-SDI (Serial Digital Interface) Electrical and Timing Characteristics

#### 3.30.1. AC and DC Characteristics

**Table 3.39. Transmit**

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
BR <sub>SDO</sub>	Serial data rate	—	270	—	2975	Mb/s
T <sub>JALIGNMENT</sub> <sup>2</sup>	Serial output jitter, alignment	270 Mb/s <sup>6</sup>	—	—	0.2	UI
T <sub>JALIGNMENT</sub> <sup>2</sup>	Serial output jitter, alignment	1485 Mb/s	—	—	0.2	UI
T <sub>JALIGNMENT</sub> <sup>1, 2</sup>	Serial output jitter, alignment	2970 Mb/s	—	—	0.3	UI
T <sub>JTIMING</sub>	Serial output jitter, timing	270 Mb/s <sup>6</sup>	—	—	0.2	UI
T <sub>JTIMING</sub>	Serial output jitter, timing	1485 Mb/s	—	—	1	UI
T <sub>JTIMING</sub>	Serial output jitter, timing	2970 Mb/s	—	—	2	UI

**Notes:**

1. Timing jitter is measured in accordance with SMPTE serial data transmission standards.
2. Jitter is defined in accordance with SMPTE RP1 184-1996 as: jitter at an equipment output in the absence of input jitter.
3. All Tx jitter are measured at the output of an industry standard cable driver, with the Lattice SERDES device configured to 50 Ω output impedance connecting to the external cable driver with differential signaling.
4. The cable driver drives: RL=75 Ω, AC-coupled at 270, 1485, or 2970 Mb/s.
5. All LFE5UM/LFE5UM5G devices are compliant with all SMPTE compliance tests, except 3G-SDI Level-A pathological compliance pattern test.
6. 270 Mb/s is supported with Rate Divider only.

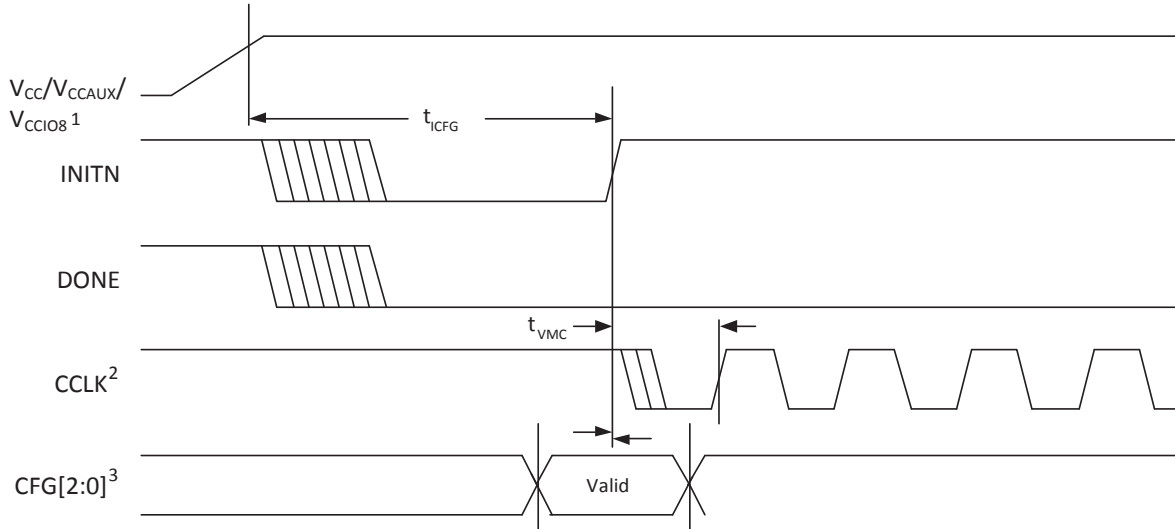
**Table 3.40. Receive**

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
BR <sub>SDI</sub>	Serial input data rate	—	270	—	2970	Mb/s

**Table 3.41. Reference Clock**

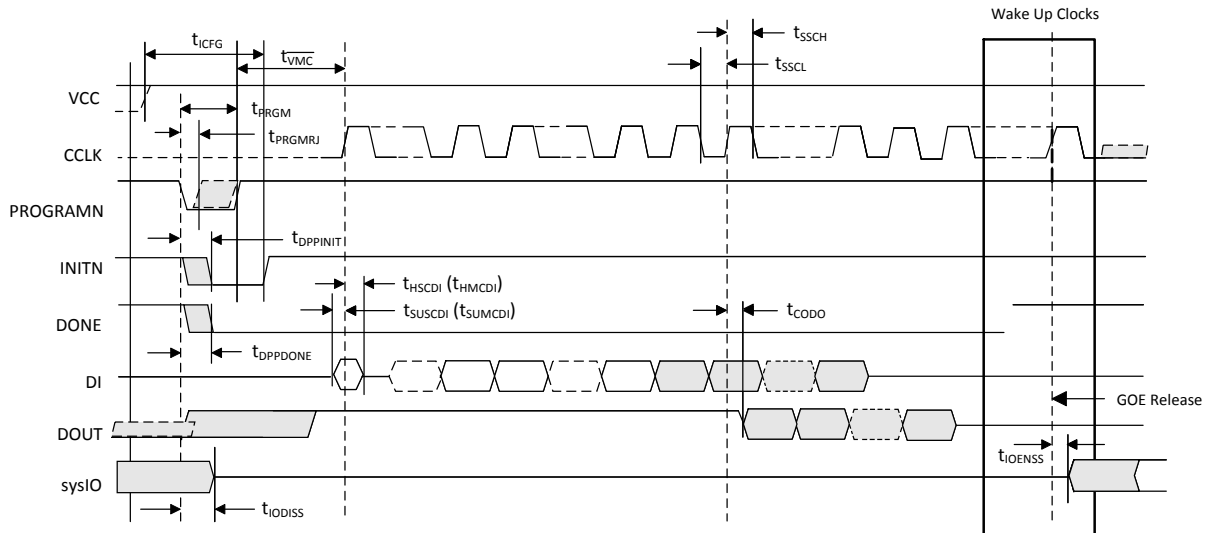
Symbol	Description	Test Conditions	Min	Typ	Max	Unit
F <sub>VCLK</sub>	Video output clock frequency	—	54	—	148.5	MHz
DC <sub>v</sub>	Duty cycle, video clock	—	45	50	55	%

**Note:** SD-SDI (270 Mb/s) is supported with Rate Divider only. For Single Rate: Reference Clock = 54 MHz and Rate Divider = /2. For Tri-Rate: Reference Clock = 148.5 MHz and Rate Divider = /11.



1. Time taken from  $V_{CC}$ ,  $V_{CCAUX}$  or  $V_{CCIOB}$ , whichever is the last to cross the POR trip point.
2. Device is in a Master Mode (SPI, SPI<sub>m</sub>).
3. The CFG pins are normally static (hardwired).

**Figure 3.18. Power-On-Reset (POR) Timing**



**Figure 3.19. sysCONFIG Port Timing**

Part number	Grade	Package	Pins	Temp.	LUTs (K)	SERDES
LFE5U-45F-8BG554C	-8	Lead free caBGA	554	Commercial	44	No
LFE5U-85F-6MG285C	-6	Lead free csfBGA	285	Commercial	84	No
LFE5U-85F-7MG285C	-7	Lead free csfBGA	285	Commercial	84	No
LFE5U-85F-8MG285C	-8	Lead free csfBGA	285	Commercial	84	No
LFE5U-85F-6BG381C	-6	Lead free caBGA	381	Commercial	84	No
LFE5U-85F-7BG381C	-7	Lead free caBGA	381	Commercial	84	No
LFE5U-85F-8BG381C	-8	Lead free caBGA	381	Commercial	84	No
LFE5U-85F-6BG554C	-6	Lead free caBGA	554	Commercial	84	No
LFE5U-85F-7BG554C	-7	Lead free caBGA	554	Commercial	84	No
LFE5U-85F-8BG554C	-8	Lead free caBGA	554	Commercial	84	No
LFE5U-85F-6BG756C	-6	Lead free caBGA	756	Commercial	84	No
LFE5U-85F-7BG756C	-7	Lead free caBGA	756	Commercial	84	No
LFE5U-85F-8BG756C	-8	Lead free caBGA	756	Commercial	84	No
LFE5UM-25F-6MG285C	-6	Lead free csfBGA	285	Commercial	24	Yes
LFE5UM-25F-7MG285C	-7	Lead free csfBGA	285	Commercial	24	Yes
LFE5UM-25F-8MG285C	-8	Lead free csfBGA	285	Commercial	24	Yes
LFE5UM-25F-6BG381C	-6	Lead free caBGA	381	Commercial	24	Yes
LFE5UM-25F-7BG381C	-7	Lead free caBGA	381	Commercial	24	Yes
LFE5UM-25F-8BG381C	-8	Lead free caBGA	381	Commercial	24	Yes
LFE5UM-45F-6MG285C	-6	Lead free csfBGA	285	Commercial	44	Yes
LFE5UM-45F-7MG285C	-7	Lead free csfBGA	285	Commercial	44	Yes
LFE5UM-45F-8MG285C	-8	Lead free csfBGA	285	Commercial	44	Yes
LFE5UM-45F-6BG381C	-6	Lead free caBGA	381	Commercial	44	Yes
LFE5UM-45F-7BG381C	-7	Lead free caBGA	381	Commercial	44	Yes
LFE5UM-45F-8BG381C	-8	Lead free caBGA	381	Commercial	44	Yes
LFE5UM-45F-6BG554C	-6	Lead free caBGA	554	Commercial	44	Yes
LFE5UM-45F-7BG554C	-7	Lead free caBGA	554	Commercial	44	Yes
LFE5UM-45F-8BG554C	-8	Lead free caBGA	554	Commercial	44	Yes
LFE5UM-85F-6MG285C	-6	Lead free csfBGA	285	Commercial	84	Yes
LFE5UM-85F-7MG285C	-7	Lead free csfBGA	285	Commercial	84	Yes
LFE5UM-85F-8MG285C	-8	Lead free csfBGA	285	Commercial	84	Yes
LFE5UM-85F-6BG381C	-6	Lead free caBGA	381	Commercial	84	Yes
LFE5UM-85F-7BG381C	-7	Lead free caBGA	381	Commercial	84	Yes
LFE5UM-85F-8BG381C	-8	Lead free caBGA	381	Commercial	84	Yes
LFE5UM-85F-6BG554C	-6	Lead free caBGA	554	Commercial	84	Yes
LFE5UM-85F-7BG554C	-7	Lead free caBGA	554	Commercial	84	Yes
LFE5UM-85F-8BG554C	-8	Lead free caBGA	554	Commercial	84	Yes
LFE5UM-85F-6BG756C	-6	Lead free caBGA	756	Commercial	84	Yes
LFE5UM-85F-7BG756C	-7	Lead free caBGA	756	Commercial	84	Yes
LFE5UM-85F-8BG756C	-8	Lead free caBGA	756	Commercial	84	Yes
LFE5UM5G-25F-8MG285C	-8	Lead free csfBGA	285	Commercial	24	Yes
LFE5UM5G-25F-8BG381C	-8	Lead free caBGA	381	Commercial	24	Yes
LFE5UM5G-45F-8MG285C	-8	Lead free csfBGA	285	Commercial	44	Yes
LFE5UM5G-45F-8BG381C	-8	Lead free caBGA	381	Commercial	44	Yes
LFE5UM5G-45F-8BG554C	-8	Lead free caBGA	554	Commercial	44	Yes
LFE5UM5G-85F-8MG285C	-8	Lead free csfBGA	285	Commercial	84	Yes

## Supplemental Information

### For Further Information

A variety of technical notes for the ECP5/ECP5-5G family are available.

- [High-Speed PCB Design Considerations \(TN1033\)](#)
- [Transmission of High-Speed Serial Signals Over Common Cable Media \(TN1066\)](#)
- [PCB Layout Recommendations for BGA Packages \(TN1074\)](#)
- [Minimizing System Interruption During Configuration Using TransFR Technology \(TN1087\)](#)
- [Electrical Recommendations for Lattice SERDES \(FPGA-TN-02077\)](#)
- [LatticeECP3, ECP-5 and ECP5-5G Soft Error Detection \(SED\)/Correction \(SEC\) Usage Guide \(TN1184\)](#)
- [Using TraceID \(TN1207\)](#)
- [Sub-LVDS Signaling Using Lattice Devices \(TN1210\)](#)
- [Advanced Security Encryption Key Programming Guide for ECP5, ECP5-5G, LatticeECP3, and LatticeECP2/MS Devices \(TN1215\)](#)
- [LatticeECP3, LatticeECP2/M, ECP5 and ECP5-5G Dual Boot and Multiple Boot Feature \(TN1216\)](#)
- [ECP5 and ECP5-5G sysCONFIG Usage Guide \(TN1260\)](#)
- [ECP5 and ECP5-5G SERDES/PCS Usage Guide \(TN1261\)](#)
- [ECP5 and ECP5-5G sysIO Usage Guide \(TN1262\)](#)
- [ECP5 and ECP5-5G sysClock PLL/DLL Design and Usage Guide \(TN1263\)](#)
- [ECP5 and ECP5-5G Memory Usage Guide \(TN1264\)](#)
- [ECP5 and ECP5-5G High-Speed I/O Interface \(TN1265\)](#)
- [Power Consumption and Management for ECP5 and ECP5-5G Devices \(TN1266\)](#)
- [ECP5 and ECP5-5G sysDSP Usage Guide \(TN1267\)](#)
- [ECP5 and ECP5-5G Hardware Checklist \(FPGA-TN-02038\)](#)
- [Solder Reflow Guide for Surface Mount Devices \(FPGA-TN-02041\)](#)
- [ECP5 and ECP5-5G PCI Express Soft IP Ease of Use Guidelines \(FPGA-TN-02045\)](#)
- [Programming External SPI Flash through JTAG for ECP5/ECP5-5G \(FPGA-TN-02050\)](#)
- [Adding Scalable Power and Thermal Management to ECP5 Using L-ASC10 \(AN6095\)](#)

For further information on interface standards refer to the following websites:

- JEDEC Standards (LVTTTL, LVCMOS, SSTL): [www.jedec.org](http://www.jedec.org)
- PCI: [www.pcisig.com](http://www.pcisig.com)